

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	24	size near3(reduc\$6 or decreas\$3 or lower\$4 or target)with image same ("q-table" or quantiza\$4 near3 table)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 14:42
L5	525	4 scal\$4 same target near3 size	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 14:34
L6	6	4 and scal\$4 same target near3 size	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 14:41
L7	1	6 and non-zero	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 14:44
L8	6	4 and scal\$4 same (target near3 (size or value))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 14:43
L9	56	(size near3(reduc\$6 or decreas\$3 or lower\$4 or target)) same ("q-table" or quantiza\$4 near3 table)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 14:43
L10	7	9 and scal\$4 same (target near3 (size or value))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 15:27
L11	2	10 and non-zero	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 14:44
L12	2	(estimat\$6 near3 reduc\$4 with scal\$4 near3 factor) same target near3 size	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/24 17:45

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)

 Welcome
 United States Patent and Trademark Office


» Se.

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

 Your search matched **4** of **1105713** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard
1 **Learning DFA: evolution versus evidence driven state merging**
Lucas, S.M.; Reynolds, T.J.;

 Evolutionary Computation, 2003. CEC '03. The 2003 Congress on , Volume: 1
 12 Dec. 2003

Pages:351 - 358 Vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(1616 KB\)\]](#) **IEEE CNF**
2 **A 3D graphics library for 32-bit microprocessors for embedded systems**
Yoshida, K.; Sakamoto, T.; Hase, T.;

 Consumer Electronics, IEEE Transactions on , Volume: 44 , Issue: 3 , Aug. 19
 Pages:1107 - 1114

[\[Abstract\]](#) [\[PDF Full-Text \(680 KB\)\]](#) **IEEE JNL**
3 **Minimizing energy consumption for high-performance processing**
Weglarz, E.F.; Saluja, K.K.; Lipasti, M.H.;

Design Automation Conference, 2002. Proceedings of ASP-DAC 2002. 7th Asia South Pacific and the 15th International Conference on VLSI Design. Proceedings , 7-11 Jan. 2002

Pages:199 - 204

[\[Abstract\]](#) [\[PDF Full-Text \(281 KB\)\]](#) **IEEE CNF**
4 **Exponential scattering and K-distributed reverberation**
Abraham, D.A.; Lyons, A.P.;

 OCEANS, 2001. MTS/IEEE Conference and Exhibition , Volume: 3 , 5-8 Nov. 2
 Pages:1622 - 1628 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(609 KB\)\]](#) **IEEE CNF**